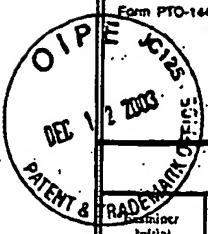


10/050 373

Form PTO-1412 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE <b>LIST OF ART CITED BY APPLICANT</b> (See several sheets of reverse)				ATTY. DOCK NICKEL	SERIAL NO 10000373		
				APPLICANT Cutter S. Schutte et al.			
				FILING DATE January 15, 2002	GROUP 2A13		
U.S. PATENT DOCUMENTS							
* Examiner's Initials	TRADE	Document Number	Date	Note	Class	Subclass	Filing Date II Appropriate
	AA	5,657,594	11/17/98	Abramski et al.	—	—	
	AB	US 6,450,116 B1	09/17/02	Niebel et al.	—	—	
	AC	4,603,447	08/12/74	Bronzetti et al.	—	—	
	AD	US 6,207,586 B1	03/27/01	Ma et al.	—	—	
	AE	3,937,592	11/17/93	Craig et al.	—	—	
	AF	3,134,354	08/02/74	Lea et al.	—	—	
	AG	US 6,297,162 B1	10/02/01	Jiang et al.	—	—	
	AH	US 6,436,771 B1	08/20/02	Jiang et al.	—	—	
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Permanent Page, Etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>hanna Schutte</i>				DATE CONSIDERED 12/16/03 2003			
<small>*EXAMINER: Initial if reference cited/relevant or file action in its enforcement can be taken. Draw line through column if not so considered. Indicate copy of this form with next communication as applicable.</small>							



U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. M22-1896		SERIAL NO. (103511)373	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Ganz, S. Sandhu et al.			
				FILING DATE January 15, 2002		GROUP 2813	
U.S. PATENT DOCUMENTS							
Reference Number		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>AA</i>	AA	6,171,900 B1	01/01	Sun	—	—	
<i>AB</i>	AB						
<i>AC</i>	AC						
<i>AD</i>	AD						
<i>AE</i>	AE						
<i>AF</i>	AF						
<i>AG</i>	AG						
<i>AH</i>	AH						
<i>AI</i>	AI						
<i>AJ</i>	AJ						
<i>AK</i>	AK						
<i>AL</i>	AL						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
<i>AM</i>	AM					Yes	No
<i>AN</i>	AN						
<i>AO</i>	AO						
<i>AP</i>	AP						
<i>AQ</i>	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>AR</i>	AR						
<i>AS</i>	AS						
<i>AT</i>	AT						
EXAMINER <i>hanna Schley</i>				DATE CONSIDERED <i>4/27/04</i>			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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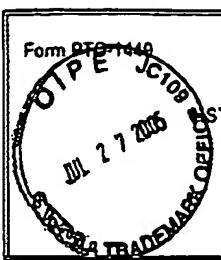
Form PTO-1449 <i>[Handwritten signatures over stamp]</i>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1896	SERIAL NO. 10/050,373		
LIST OF REFERENCES BY APPLICANT (Use several sheets if necessary)				APPLICANT: Gurtej S. Sandhu, et al.			
				FILING DATE January 15, 2002	GROUP 2813		
<b>U.S. PATENT DOCUMENTS</b>							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>AM</i>	A	3,627,598	12/1971	McDonald, et al.	—	—	
<i>AM</i>	AB	4,254,161	03/1981	Kemlage	—	—	
<i>AM</i>	AC	4,262,631	04/1981	Kubacki	—	—	
<i>AM</i>	AD	4,435,447	03/1984	Ito, et al.	—	—	
<i>AM</i>	AE	4,882,649	11/1989	Chen, et al.	—	—	
<i>AM</i>	AF	4,891,684	01/1990	Nishioka, et al	—	—	
<i>AM</i>	AG	4,980,307	12/1990	Ito, et al.	—	—	
<i>AM</i>	AH	4,995,081	02/1991	Eliel, et al.	—	—	
<i>AM</i>	A	5,051,794	09/1991	Mori	—	—	
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Subclass	Translation
<i>AM</i>	A	EP 0886308 A2	12/1998	Europe	—	—	
<i>AM</i>	AK	237243 a	04/2001	Japan (ASM America, Inc.)	—	—	
	A				—	—	
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
<i>AM</i>	AM	Wolf, Stanley, "Silicon Processing for the VLSI Era, Volume 3: The Submicron Mosfet", Lattice Press, 1995, pages 648-9.					
		Laughery, et al, "Effect of H <sub>2</sub> Content on Reliability of Ultrathin In-Situ Steam Generated (ISSG) SiO <sub>2</sub> ", EEE Electron Device Letters, September, 2000, Volume 21, No. 9.					
	AN						
	AO						
EXAMINER <i>Hansen</i> <i>Schiffge</i>	DATE CONSIDERED <i>11/25/05</i>						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE <small>SEARCHED &amp; SERIALIZED</small> <small>JUL 27 2005</small> <small>USPTO - CANCELLER</small> <small>JUL 16 2005</small> <small>COPYRIGHT SEARCHED</small> <small>JUL 16 2005</small> <small>LIST OF ART CITED BY APPLICANT</small> <small>(Use several sheets if necessary)</small>					ATTY. DOCKET NO. MI22-1896	SERIAL NO. 10/050,373	
					APPLICANT: Gurtej S. Sandhu, et al.		
					FILING DATE January 15, 2002	GROUP 2813	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>AM</i>	AA	5,142,438	08/1992	Reinberg, et al.			
<i>AM</i>	AB	5,227,651	07/1993	Kim, et al.			
<i>AC</i>	AC	5,237,188	08/1993	Iwai, et al.			
<i>AD</i>	AD	5,324,679	06/1994	Kim, et al.			
<i>AE</i>	AE	5,330,936	07/1994	Ishitanti			
<i>AF</i>	AF	5,350,707	09/1994	Ko, et al.			
<i>AG</i>	AG	5,376,593	12/1994	Sandhu, et al.			
<i>AH</i>	AH	5,393,702	02/1995	Yang, et al.			
<i>AI</i>	AI	5,397,748	03/1995	Watanabe, et al.			
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Subclass	Translation
	AK						Yes
	AL						No
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER <i>newer scully</i>	AM						
	AN						
AO							
EXAMINER <i>newer scully</i>	DATE CONSIDERED <i>11/25/05</i>						
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449  <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b> <b>JUL 27 2005</b> <b>LIST OF ART CATEGORIES APPLICANT</b> <small>(Use additional sheets if necessary)</small>				ATTY. DOCKET NO. MI22-1896	SERIAL NO. 10/050,373		
				APPLICANT: Gurtej S. Sandhu, et al.			
				FILING DATE January 15, 2002	GROUP 2813		
<b>U.S. PATENT DOCUMENTS</b>							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>elle</i>	AA	5,398,641	03/1995	Shih			
	AB	5,459,105	10/1995	Matsuura			
	AC	5,498,890	03/1996	Kim, et al.			
	AD	5,504,029	04/1996	Murata, et al.			
	AE	5,508,542	04/1996	Geiss, et al.			
	AF	5,523,596	06/1996	Ohi, et al.			
	AG	5,731,235	03/1998	Srinivasan, et al.			
	AH	5,821,142	10/1998	Sung, et al.			
<i>elle</i>	N	5,844,771	12/1998	Graettinger, et al.			
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Subclass	Translation
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	AK						No
	AL						
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	AA						
	AM						
	AO						
EXAMINER <i>harry scutty</i>	DATE CONSIDERED	<i>11/05/05</i>					
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1895	SERIAL NO. 10/050,373		
LIST OF ART CITED BY APPLICANT <small>(Use separate sheet if necessary)</small>		APPLICANT: Gurje S. Sandhu, et al.					
		FILING DATE January 15, 2002	GROUP 2813				
<b>U.S. PATENT DOCUMENTS</b>							
*Examiner's Initials		Document Number	Date	Name	Class      Subclass If Appropriate		
<i>JLle</i>	AA	5,851,603	12/1998	Tsai, et al.	_____		
	AB	5,882,978	03/1999	Srinivasan, et al.	_____		
	AC	6,001,741	12/1999	Aiers	_____		
	AD	6,001,748	12/1999	Tanaka	_____		
	AE	6,008,104	12/1999	Schrems	_____		
	AF	6,051,865	04/2000	Gardner, et al.	_____		
	AG	6,063,713	06/2000	Doan	_____		
	AH	6,077,754	06/2000	Srinivasan, et al.	_____		
<i>JLle</i>	AI	6,090,597	08/2000	Tsu, et al.	_____		
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class      Subclass	Translation	
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	AK						
	AL						
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	AM						
	AN						
	AO						
EXAMINER <i>Horacio Schreyer</i>	DATE CONSIDERED <i>11/25/05</i>						
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Form PTO-1449 <i>OJIP E JUL 27 2005</i> U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1898	SERIAL NO. 10/050,373				
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT: Gurtej S. Sandhu, et al.					
		FILING DATE January 15, 2002	GROUP 2813				
<b>U.S. PATENT DOCUMENTS</b>							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>JLle</i>	AM	6,111,744	08/2000	Dean			
	AB	6,168,980	01/2001	Yamazaki, et al.			
	AC	6,207,985 B1	03/2001	Walker			
	AD	6,323,138 B1	11/2001	Dean			
	AE	6,348,420 B1	02/2002	Raaijmakers, et al.			
	AF	6,265,327	07/2001	Kobayashi, et al.			
	AG	6,350,707 B1	02/2002	Liu, et al.			
	AH	6,723,599 B2	04/2004	Eppich, et al.			
<i>JLle</i>	AN	6,893,981 B2	05/2005	Park, et al.			
<b>FOREIGN PATENT DOCUMENTS</b>				Country	Class	Subclass	Translation
		Document Number	Date				Yes      No
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	AM						
	AN						
	AO						
EXAMINER <i>hawea</i> <i>Salukesh</i>	DATE CONSIDERED	<i>11/25/05</i>					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



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PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
MI22-1896

SERIAL NO.  
10/050,373

LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Gurtej S. Sandhu, et al.

FILING DATE  
January 15, 2002

GROUP  
2813

U.S. PATENT DOCUMENTS

Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>JL</i>	AA	09/653,281	08/2000	Beaman, et al.	—	—	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AJ						No
	AK						
	AL						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AM		
	AM		
	AO		
EXAMINER <i>reema Schleyer</i>	DATE CONSIDERED	11/05/05	

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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1896SERIAL NO.  
10/050,373LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Gurje S. Sandhu, et al.

FILING DATE  
January 15, 2002GROUP  
2813

## PATENT DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>AM</i>	AA	2001/0036752	11/2001	DeBoer, et al.	—	—	
	AB	2002/0009861	08/1998	Narwankar, et al.	—	—	
	AC	2002/0052124	05/2002	Raaijmakers, et al.	—	—	
<i>AM</i>	AD	2003/0034518A1	02/2003	Yoshikawa	—	—	
	AE						
	AF						
	AG						
	AH						
	AI						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AA							
	AB							
	AC							
	AD							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AM			
AM			
AD			

EXAMINER *Schulz*

DATE CONSIDERED

11/25/05

'EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 <i>O I P E</i> FEB 28 2006 U.S. PATENT & TRADEMARK OFFICE		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1896	SERIAL NO. 10/050,373
				APRIL 8 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)	
				APPLICANT: Gurtej S. Sandhu, et al.	
				FILING DATE January 15, 2002	ART GROUP 2813

## U.S. PATENT DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>SL</i>	AA	5,897,354	04/99	Kachelmeier, Mark T.			
	AB	5,920,779	07/99	Sun, et al.			
	AC	5,969,397	10/99	Grider, III, et al.			
	AD	5,981,366	11/99	Koyama, et al.			
	AE	6,040,249	03/00	Holloway			
	AF	6,087,236	07/00	Chau, et al.			
	AG	6,150,266 (MI22-810)	11/00	Reinberg			
	AH	6,245,616 B1	06/01	Buchanan, et al.			
	AI	6,875,707 (MI22-2304)	04/05	Moore, et al.			
	AJ	6,878,585 (MI22-1776)	04/05	Moore, et al.			
<i>V</i>	AK	6,891,215 (MI22-2305)	05/05	Moore, et al.			
<i>SL</i>	AL	2005/0167727 A1 (MI22-2849)	08/05	Moore, et al.			

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>SL</i>	AL							
	AM							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>SL</i>	AN	
	AO	

EXAMINER DATE CONSIDERED

*hawea Schulyer**8/3/06*

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